

Notice of References Cited

Application/Control No.

10/565,323

Applicant(s)/Patent Under
Reexamination
SAWADA ET AL.

Examiner

Bijan Ahvazi

Art Unit

1796

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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	G	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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